


<b>Search Notes</b>  	<b>Application/Control No.</b>  10560964	<b>Applicant(s)/Patent Under Reexamination</b>  YOON ET AL.
	<b>Examiner</b>  David M Brunsman	<b>Art Unit</b>  1793

SEARCHED			
Class	Subclass	Date	Examiner
106	162.2	11-22-2008	DB
502	62,401,404	11-22-2008	DB

SEARCH NOTES		
Search Notes	Date	Examiner
eDan inventor name search	11-22-2008	DB
EAST text search - see attached printout	11-24-2008	DB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
106	162.2	11-22-2008	DB
502	62,401,404	11-22-2008	DB

--	--